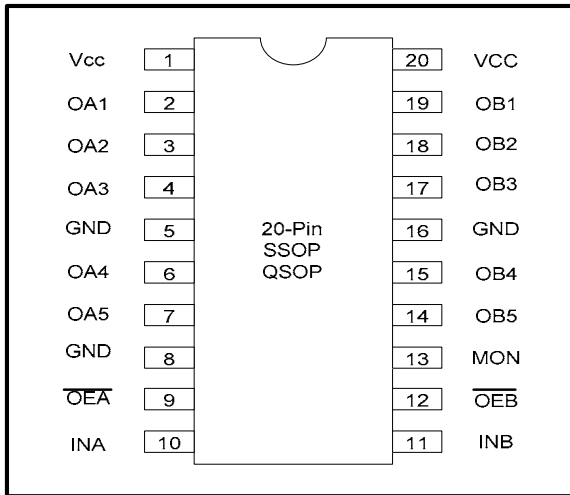


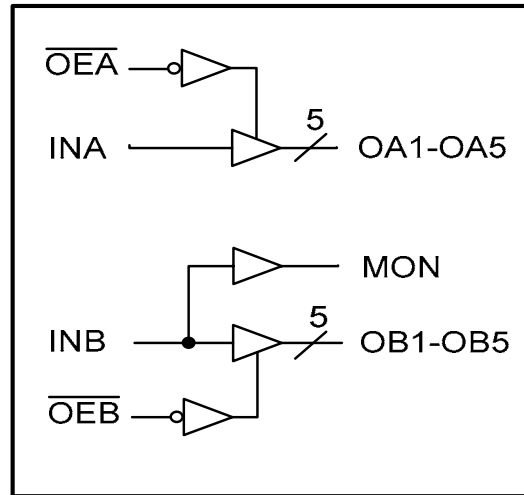
600MHz TTL/CMOS Potato Chip

FEATURES:	DESCRIPTION:
<ul style="list-style-type: none"> . Operating frequency up to 600MHz with 2pf load . Operating frequency up to 500MHz with 5pf load . Operating frequency up to 270MHz with 15pf load . Operating frequency up to 120MHz with 50pf load . Very low output pin to pin skew < 250ps . Very low pulse skew < 200ps . VCC = 1.65V to 3.6V . Propagation delay < 2.6ns max with 15pf load . Low input capacitance: 3pf typical . Dual 1:5 fanout . Available in 20pin 300mil wide SOIC package . Available in 20pin 150mil wide QSOP package 	<p>Potato Semiconductor's PO49FCT32805G is designed for world top performance using submicron CMOS technology to achieve 600MHz TTL output frequency with less than 200ps output pulse skew.</p> <p>PO49FCT32805G is a 3.3V CMOS Dual 1 input to 5 outputs Buffered driver to achieve 600MHz output frequency with integrated series damping resistors on all outputs to match 50 ohm transmission line impedance. Typical applications are clock and signal distribution.</p>

Pin Configuration



Logic Block Diagram



Pin Description

Pin Name	Description
INA, INB	Signal or clock Inputs
\overline{OEA} , \overline{OEB}	Hi-Z State Output Enable Inputs (Active LOW)
OAn, OBn	Signal or clock Outputs
MON	Monitor Output
Vcc, GND	Power, Ground

Inputs		Outputs	
\overline{OEA} , \overline{OEB}	INA, INB	OAn, OBn	MON
L	L	L	L
L	H	H	H
H	L	Z	L
H	H	Z	H

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Maximum Ratings

Description	Max	Unit
Storage Temperature	-65 to 150	°C
Operation Temperature	-40 to 85	°C
Operation Voltage	-0.5 to +4.6	V
Input Voltage	-0.5 to V _{cc} +0.5	V
Output Voltage	-0.5 to V _{cc} +0.5	V

Note:

stresses greater than listed under Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability specification is not implied.

DC Electrical Characteristics

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
V_{OH}	Output High voltage	V _{cc} =3V Vin=V _{IH} or V _{IL} , I _{OH} = -8mA	2.4	3	-	V
V_{OL}	Output Low voltage	V _{cc} =3V Vin=V _{IH} or V _{IL} , I _{OH} =12mA	-	0.3	0.5	V
V_{IH}	Input High voltage	Guaranteed Logic HIGH Level (Input Pin)	2	-	V_{cc}	V
V_{IL}	Input Low voltage	Guaranteed Logic LOW Level (Input Pin)	-0.5	-	0.8	V
I_{IH}	Input High current	V _{cc} = 3.6V and Vin = 3.6V	-	-	1	uA
I_{IOZH}	High Impedance Output current	V _{cc} = 3.6V and Vo = V _{cc}	-	-	1	uA
I_{IOZL}	High Impedance Output current	V _{cc} = 3.6V and Vo = 0V	-	-	-1	uA
I_{IL}	Input Low current	V _{cc} = 3.6V and Vin = 0V	-	-	-1	uA
V_{IK}	Clamp diode voltage	V _{cc} = Min. And I _{IN} = -18mA	-	-0.7	-1.2	V

Notes:

1. For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at V_{cc} = 3.3V, 25 °C ambient.
3. This parameter is guaranteed but not tested.
4. Not more than one output should be shorted at one time. Duration of the test should not exceed one second.
5. VoH = V_{cc} - 0.6V at rated current

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Power Supply Characteristics

Symbol	Description	Test Conditions (1)	Min	Typ	Max	Unit
IccQ	Quiescent Power Supply Current	Vcc=Max, Vin=Vcc or GND	-	0.1	30	uA

Notes:

1. For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at Vcc = 3.3V, 25°C ambient.
3. This parameter is guaranteed but not tested.
4. Not more than one output should be shorted at one time. Duration of the test should not exceed one second.

Capacitance (TA= +25°C, f= 1MHz)

Parameters (1)	Description	Test Conditions	Typ	Max	Unit
Cin	Input Capacitance	Vin = 0V	3	4	pF
Cout	Output Capacitance	Vout = 0V	-	6	pF

Notes:

- 1 This parameter is determined by device characterization but not production tested.

Switching Characteristics

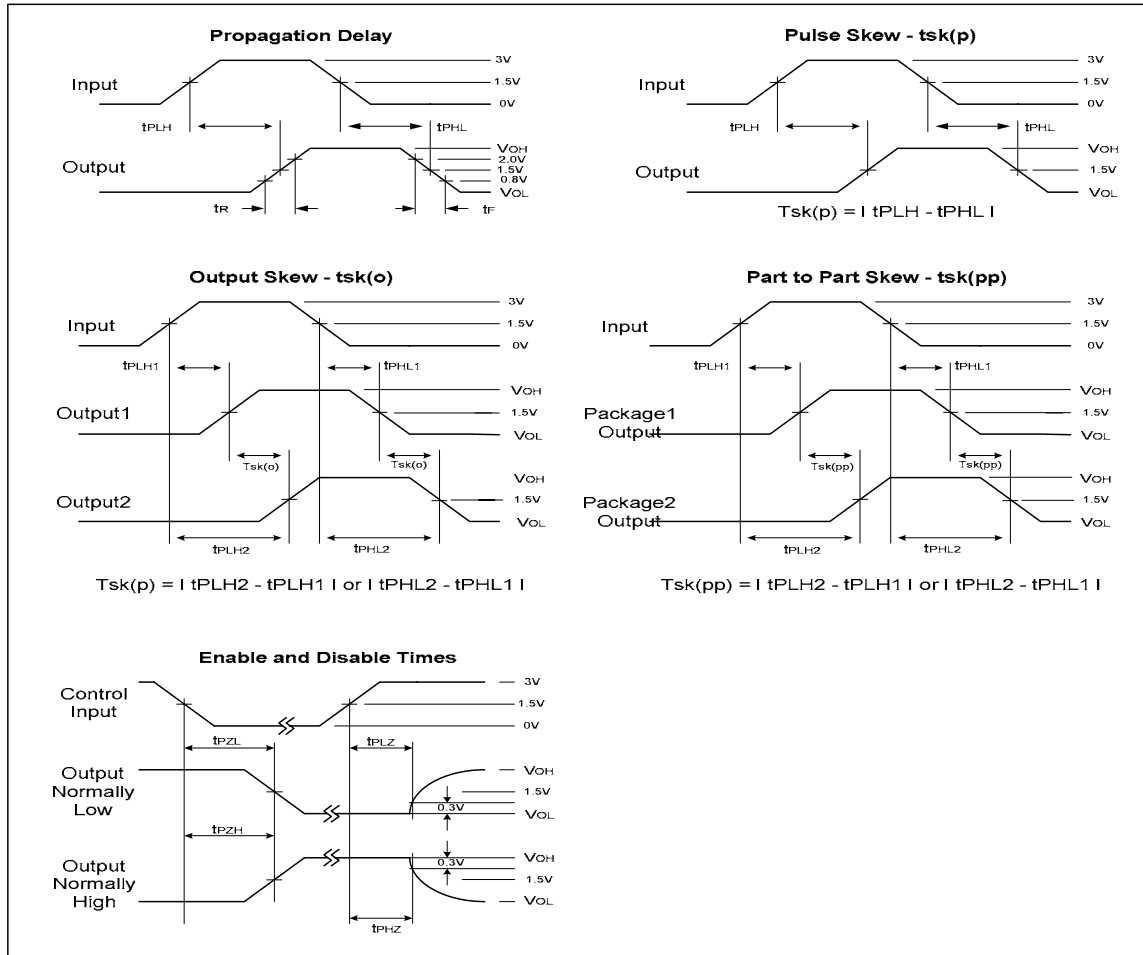
Symbol	Description	Test Conditions (1)	Max	Unit
tPLH & tPHL	Propagation Delay INA to OAn, INB to OBn	CL = 15pF	2.6	ns
tpZH or tpZL	Output Enable Time	CL = 15pF	2.5	ns
tpHZ or tPLZ	Output Disable Time	CL = 15pF	2.5	ns
tr/tf	Rise/Fall Time	0.8V – 2.0V	1	ns
tsk(p)	Pulse Skew (Same Package)	CL = 15pF, 125MHz	0.2	ns
tsk(o)	Output Pin to Pin Skew (Same Package)	CL = 15pF, 125MHz	0.25	ns
tsk(pp)	Output Skew (Different Package)	CL = 15pF, 125MHz	0.4	ns
fmax	Input Frequency	CL = 50pF	120	MHz
fmax	Input Frequency	CL = 15pF	270	MHz
fmax	Input Frequency	CL = 5pF	500	MHz
fmax	Input Frequency	CL = 2pF	600	MHz

Notes:

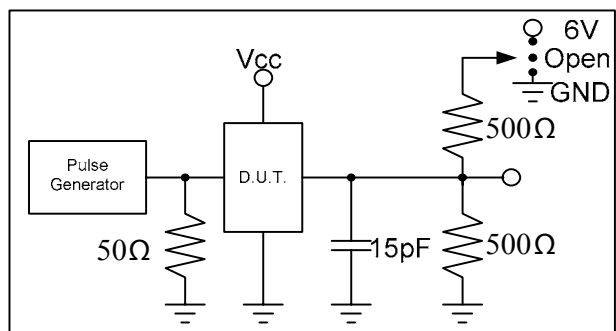
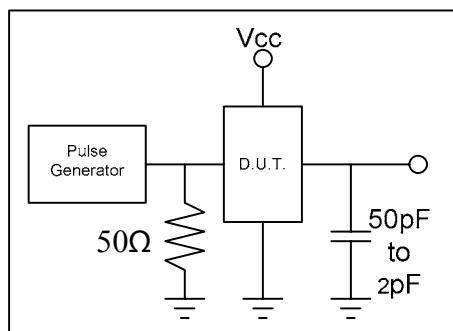
1. See test circuits and waveforms.
2. tpLH, tPHL, tsk(p), and tsk(o) are production tested. All other parameters guaranteed but not production tested.
3. Airflow of 1m/s is recommended for frequencies above 133MHz

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Test Waveforms

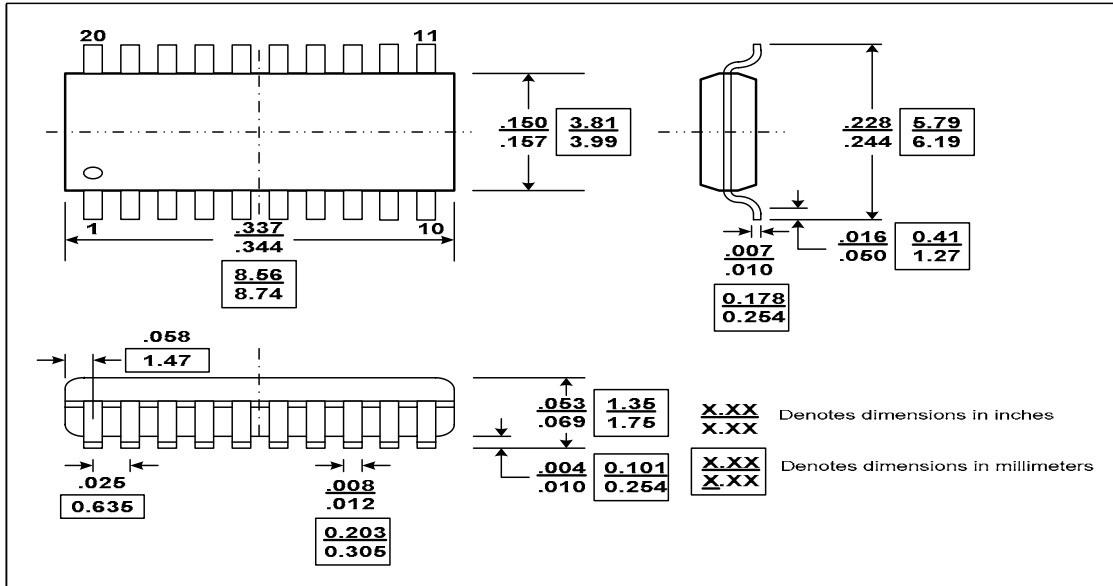


Test Circuit

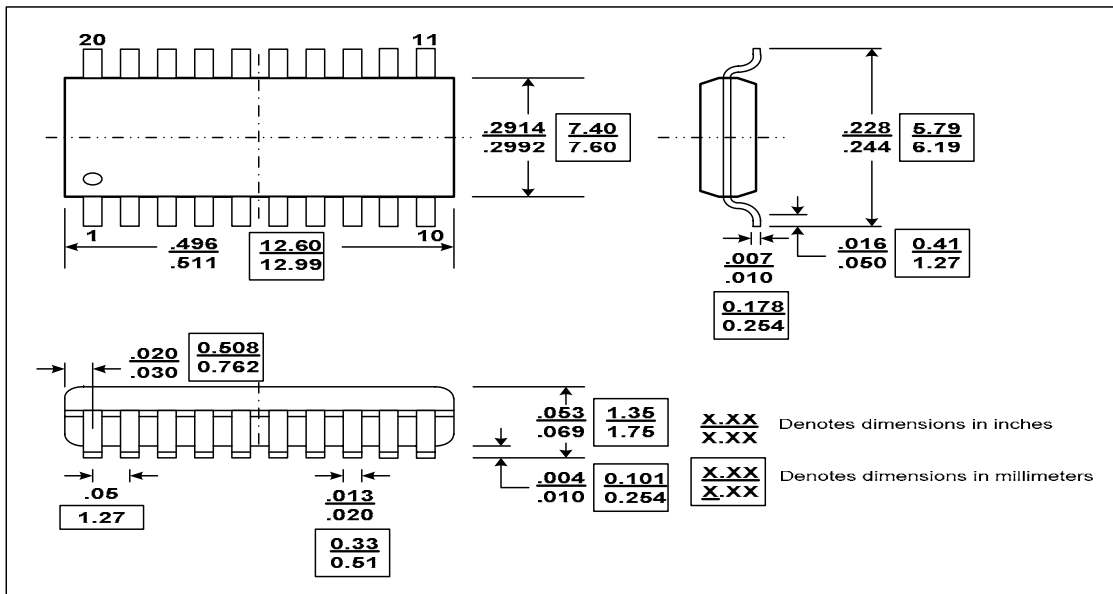


600MHz TTL/CMOS Potato Chip

Packaging Mechanical Drawing: 20 pin QSOP



Packaging Mechanical Drawing: 20 pin SOIC



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Ordering Information

Ordering Code	Package Code	Package Description
PO49FCT32805S	S	Pb-free & Green, 20-pin SOIC
PO49FCT32805Q	Q	Pb-free & Green, 20-pin QSOP